# International IOR Rectifier

### **PRELIMINARY**

# IRFR/U9024N

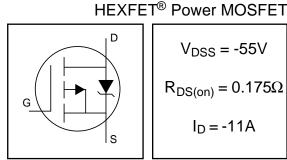
#### Ultra Low On-Resistance

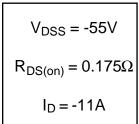
- P-Channel
- Surface Mount (IRFR9024N)
- Straight Lead (IRFU9024N)
- Advanced Process Technology
- Fast Switching
- Fully Avalanche Rated

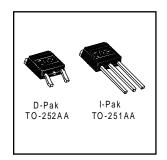
#### **Description**

Fifth Generation HEXFETs from International Rectifier utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET Power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

The D-Pak is designed for surface mounting using vapor phase, infrared, or wave soldering techniques. The straight lead version (IRFU series) is for throughhole mounting applications. Power dissipation levels up to 1.5 watts are possible in typical surface mount applications.







### **Absolute Maximum Ratings**

	Parameter	Max.	Units	
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ -10V	-11		
I <sub>D</sub> @ T <sub>C</sub> = 100°C	Continuous Drain Current, V <sub>GS</sub> @ -10V	-8	Α	
I <sub>DM</sub>	Pulsed Drain Current ①	-44		
P <sub>D</sub> @T <sub>C</sub> = 25°C	Power Dissipation	38	W	
	Linear Derating Factor	0.30	W/°C	
$V_{GS}$	Gate-to-Source Voltage	± 20	V	
E <sub>AS</sub>	Single Pulse Avalanche Energy®	62	mJ	
I <sub>AR</sub>	Avalanche Current①	-6.6	Α	
E <sub>AR</sub>	Repetitive Avalanche Energy①	3.8	mJ	
dv/dt	Peak Diode Recovery dv/dt ③	-10	V/ns	
TJ	Operating Junction and	-55 to + 150		
T <sub>STG</sub>	Storage Temperature Range		°C	
	Soldering Temperature, for 10 seconds	300 (1.6mm from case )	1	

#### Thermal Resistance

	Parameter	Тур.	Max.	Units
R <sub>θ</sub> JC	Junction-to-Case		3.3	
$R_{\theta JA}$	Junction-to-Ambient (PCB mount)**		50	°C/W
$R_{\theta JA}$	Junction-to-Ambient		110	

## Electrical Characteristics @ T<sub>J</sub> = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
V <sub>(BR)DSS</sub>	Drain-to-Source Breakdown Voltage	-55			V	$V_{GS} = 0V, I_{D} = -250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient		-0.05		V/°C	Reference to 25°C, I <sub>D</sub> = -1mA
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance			0.175	Ω	V <sub>GS</sub> = -10V, I <sub>D</sub> = -6.6A ④
V <sub>GS(th)</sub>	Gate Threshold Voltage	-2.0		-4.0	V	$V_{DS} = V_{GS}$ , $I_D = -250\mu A$
9 <sub>fs</sub>	Forward Transconductance	2.5			S	V <sub>DS</sub> = -25V, I <sub>D</sub> = -7.2A®
L	Drain-to-Source Leakage Current			-25	μA	$V_{DS} = -55V, V_{GS} = 0V$
I <sub>DSS</sub>	Diam-to-Source Leakage Current			-250	"^	$V_{DS} = -44V, V_{GS} = 0V, T_{J} = 150^{\circ}C$
	Gate-to-Source Forward Leakage			100	nA	V <sub>GS</sub> = 20V
I <sub>GSS</sub>	Gate-to-Source Reverse Leakage			-100	IIIA	V <sub>GS</sub> = -20V
Qg	Total Gate Charge			19		I <sub>D</sub> = -7.2A
Q <sub>gs</sub>	Gate-to-Source Charge			5.1	nC	$V_{DS} = -44V$
$Q_{gd}$	Gate-to-Drain ("Miller") Charge			10		V <sub>GS</sub> = -10V, See Fig. 6 and 13 ⊕ ®
t <sub>d(on)</sub>	Turn-On Delay Time		13			$V_{DD} = -28V$
t <sub>r</sub>	Rise Time		55			$I_D = -7.2A$
t <sub>d(off)</sub>	Turn-Off Delay Time		23		ns	$R_G = 24\Omega$
t <sub>f</sub>	FallTime		37			$R_D = 3.7\Omega$ , See Fig. 10 $\oplus$ $\oplus$
	Internal Dunin Industria		4.5			Between lead,
L <sub>D</sub>	Internal Drain Inductance		4.5			6mm (0.25in.)
	Internal Source Inductance — 7.5		nH	from package		
L <sub>S</sub>			7.5			and center of die contact <sup>®</sup>
C <sub>iss</sub>	Input Capacitance		350			V <sub>GS</sub> = 0V
C <sub>oss</sub>	Output Capacitance		170		pF	$V_{DS} = -25V$
C <sub>rss</sub>	Reverse Transfer Capacitance		92			f = 1.0MHz, See Fig. 5®

## **Source-Drain Ratings and Characteristics**

	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current			-11		MOSFET symbol
	(Body Diode)			-11	A	showing the
I <sub>SM</sub>	Pulsed Source Current			4.4		integral reverse
	(Body Diode) ①		-44		p-n junction diode.	
V <sub>SD</sub>	Diode Forward Voltage			-1.6	V	$T_J = 25$ °C, $I_S = -7.2$ A, $V_{GS} = 0$ V ④
t <sub>rr</sub>	Reverse Recovery Time		47	71	ns	$T_J = 25^{\circ}C$ , $I_F = -7.2A$
Q <sub>rr</sub>	Reverse Recovery Charge		84	130	nC	di/dt = 100A/µs 46
t <sub>on</sub>	Forward Turn-On Time	On Time Intrinsic turn-on time is negligible (turn-on is dominated by L <sub>S</sub> +L <sub>D</sub> )				

#### Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. ( See fig. 11 )
- $\begin{tabular}{ll} \hline @ Starting $T_J = 25^\circ$C, $L = 2.8mH$\\ $R_G = 25\Omega, I_{AS} = -6.6A.$ (See Figure 12) \\ \hline \end{tabular}$
- $\ \Im \ I_{SD} \le$  -6.6A, di/dt  $\le$  240A/ $\mu s, \ V_{DD} \le V_{(BR)DSS}, \ T_J \le$  150°C
- ⓐ Pulse width ≤ 300 $\mu$ s; duty cycle ≤ 2%.
- \$This is applied for I-PAK, L<sub>S</sub> of D-PAK is measured between lead and center of die contact
- © Uses IRF9Z24N data and test conditions.
- \*\* When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994

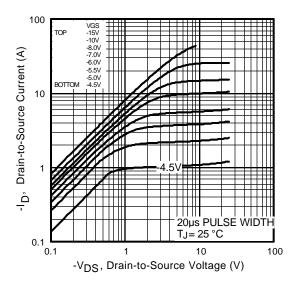


Fig 1. Typical Output Characteristics

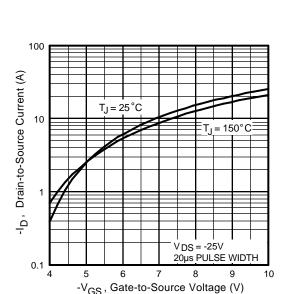


Fig 3. Typical Transfer Characteristics

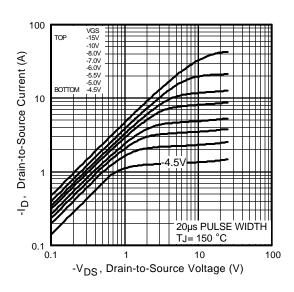
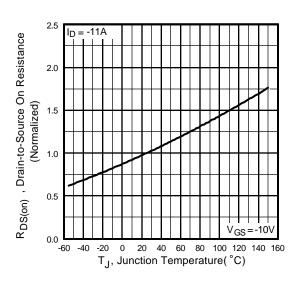
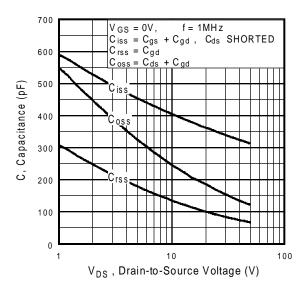


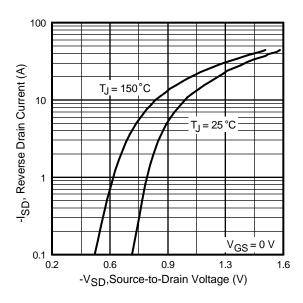
Fig 2. Typical Output Characteristics



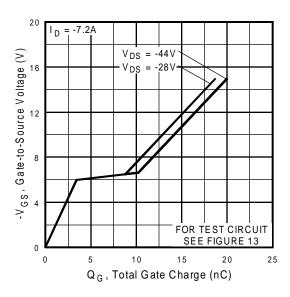
**Fig 4.** Normalized On-Resistance Vs. Temperature



**Fig 5.** Typical Capacitance Vs. Drain-to-Source Voltage



**Fig 7.** Typical Source-Drain Diode Forward Voltage



**Fig 6.** Typical Gate Charge Vs. Gate-to-Source Voltage

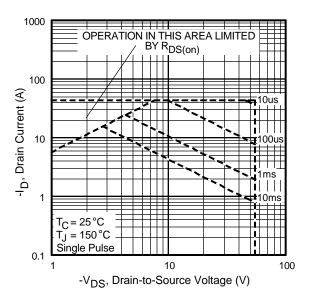
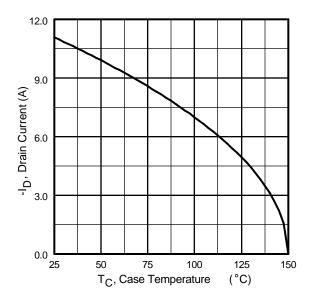


Fig 8. Maximum Safe Operating Area



**Fig 9.** Maximum Drain Current Vs. Case Temperature

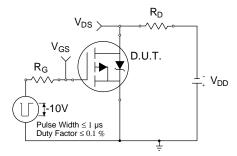


Fig 10a. Switching Time Test Circuit

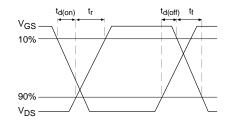


Fig 10b. Switching Time Waveforms

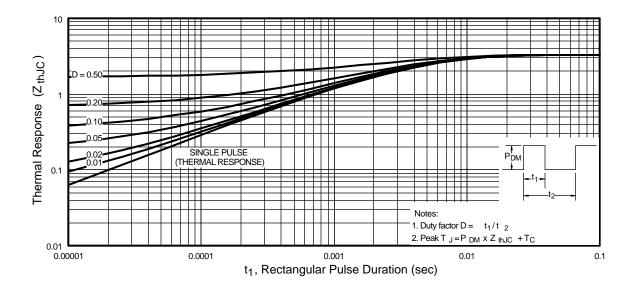


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

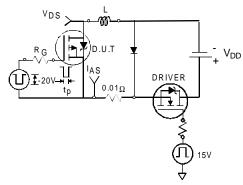


Fig 12a. Unclamped Inductive Test Circuit

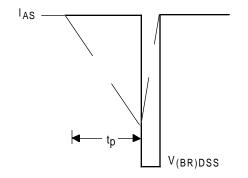


Fig 12b. Unclamped Inductive Waveforms

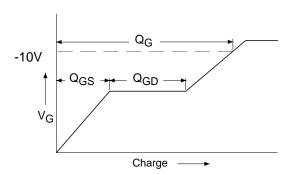
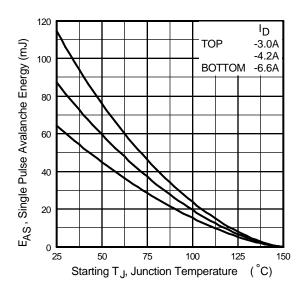


Fig 13a. Basic Gate Charge Waveform



**Fig 12c.** Maximum Avalanche Energy Vs. Drain Current

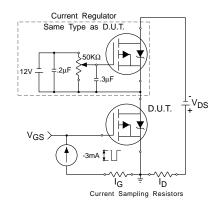
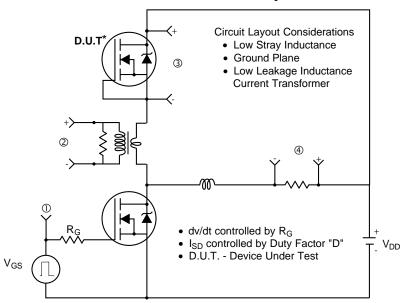
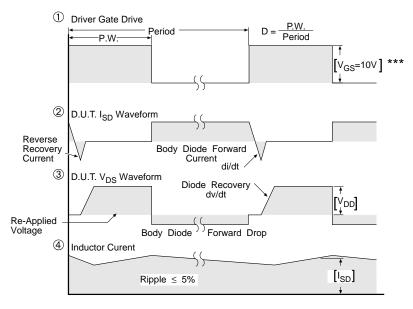


Fig 13b. Gate Charge Test Circuit

## Peak Diode Recovery dv/dt Test Circuit



<sup>\*</sup> Reverse Polarity of D.U.T for P-Channel



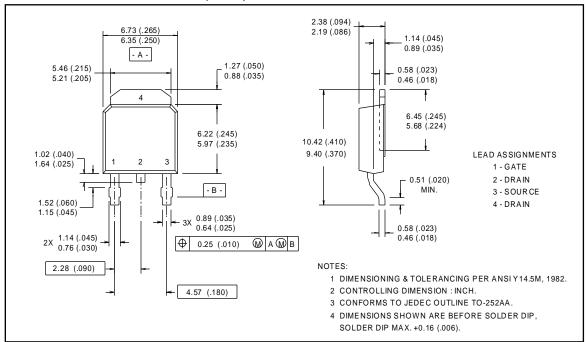
\*\*\* V<sub>GS</sub> = 5.0V for Logic Level and 3V Drive Devices

Fig 14. For P-Channel HEXFETS

# Package Outline

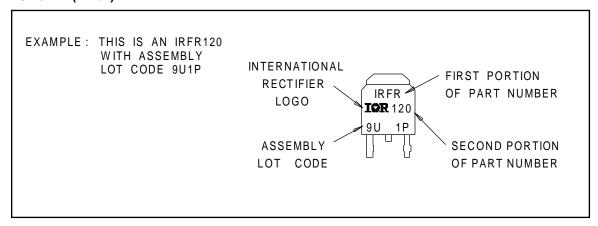
#### **TO-252AA Outline**

Dimensions are shown in millimeters (inches)



# Part Marking Information

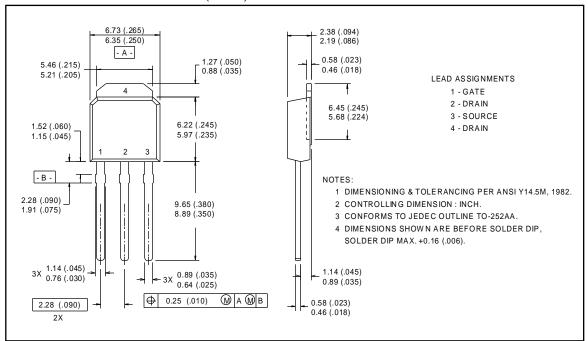
#### TO-252AA (D-Pak)



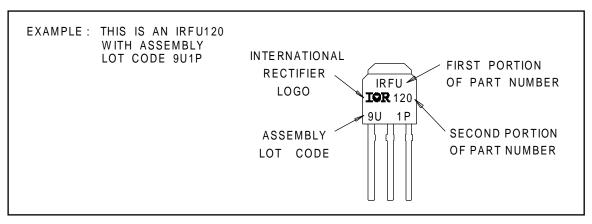
# Package Outline

#### TO-251AA Outline

Dimensions are shown in millimeters (inches)

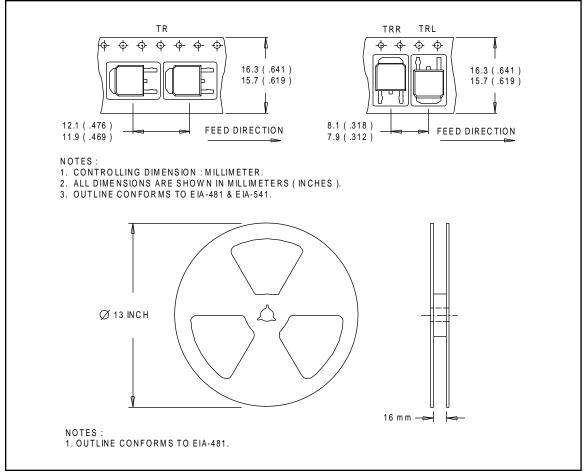


# Part Marking Information TO-251AA (I-Pak)



## **Tape & Reel Information**

#### **TO-252AA**



# International Rectifier

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